



MODEL: ADE9600 ULTRASCAN

- ▶ Deliver a completely refurbished ADE 9600 Ultrascan system
- ▶ Supported SEMI/JEIDA Geometries
 - ▶ Wafer diameters supported: 125mm, 150mm, 200mm (polished or patterned)
 - ▶ Wafer thickness: 400 um to 800 um
 - ▶ Notches, Flats(primary/Secondary): Up to four(4) per SEMI and JEIDA standards
- ▶ Edge Exclusion: To 3 mm from edge (2mm optional)
 - ▶ Measurement and sorting
 - ▶ Thickness Center point, Five point, Full wafer scan
 - ▶ Shape: Bow, Warp, using 3-point & Best-fit references
 - ▶ Global Flatness: SEMI GBI ,TIR, FPD, FPD%, 5-point TTV
 - ▶ Site Flatness: All SEMI M1 Standards with 8 – 30mm sit size and variable site offsets
- ▶ Data Density and Throughput
 - ▶ Number of thickness/shape data points: Up to 17300 points
 - ▶ Throughput using optional handler: 30 – 59+ wafer/hour (depends on wafer size, measurement pattern and mode

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System Consist of :

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Cassette input stations*2

Cassette output stations*3

Pal station *1

E-plus station *1

Rest station*1

ASC Controller*1

ADE single robot station*1

ADE robot controller*1

Main DC power*1

Delivery time: 4 months

Option Choice upgrade tools

Controller function open (edge 2mm)

Signal effector arm Robot upgrade to Dual effector arm robot

ASC Controller upgrade to ASC 2000

UPS(C-10000F)

Non-contact P/N Type tester: For wafer resistivity from 0.1 to 200 Ω cm-cm